

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10598025	DE HAAN ET AL.
	Examiner	Art Unit
	Kenneth Chang	4171

SEARCHED

Class	Subclass	Date	Examiner
380	200, 203, 210, 212, 217, 236, 239	12/23/2008	KWC
713	153, 160, 167, 170	12/23/2008	KWC
725	60, 61, 67, 68, 70, 87, 145	12/23/2008	KWC
370	321, 386	12/23/2008	KWC
382	100, 234, 235	12/23/2008	KWC
705	57, 59, 405	12/23/2008	KWC

SEARCH NOTES

Search Notes	Date	Examiner
Requested NPL STIC PLUS Search.	12/22/2008	KWC
Searched USPAT AND PGPUB Databases for Class 380 Subclasses 200, 203, 210, 212, 217, 236, 239; Class 725 Subclasses 60, 61, 67, 68, 87, 145; Class 713 Subclasses 153, 160, 167, 170; Class 370 Subclasses 321, 386; Class 382 Subclasses 100, 234, 235; Class 705 Subclasses 57, 59, 405. Class 726	12/23/2008	KWC
Searched NPL IEEEXplore.	12/23/2008	KWC

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner